

## IEC SYSTEM FOR MUTUAL RECOGNITION OF TEST CERTIFICATES FOR ELECTRICAL EQUIPMENT (IECEE) CB SCHEME

## CB TEST CERTIFICATE

Product

Intel® NUC

Name and address of the applicant

INTEL CORPORATION  
2200 MISSION COLLEGE BLVD SANTA CLARA, CA  
95054-1537 USA

Name and address of the manufacturer

INTEL CORPORATION  
2200 MISSION COLLEGE BLVD SANTA CLARA, CA  
95054-1537 USA

Name and address of the factory

Note: When more than one factory, please report on page 2

GOLDEN ELITE TECHNOLOGY (SHEN ZHEN) LTD  
1 NAN HUAN RD SHAJING BAO AN SHENZHEN GUANGDONG  
518104  
CHINA Additional Information on page 2

Ratings and principal characteristics

- 1) 19 Vdc., 3.43 A
- 2) 19 Vdc., 3.42 A
- 3) 19 Vdc., 4.74 A

Trademark (if any)



Type of Customer's Testing Facility (CTF) Stage used

Model / Type Ref.

- 1) xNUC6xAYx, xNUC7xBNHx, xNUC7xBNKx
  - 2) xNUC7xJYx
  - 3) xNUC8xBEHx, xNUC8xBEKx
- See Page 2

Additional information (if necessary may also be reported on page 2)

 Additional Information on page 2

A sample of the product was tested and found to be in conformity with

IEC 60950-1(ed.2), IEC 60950-1(ed.2);am1, IEC 60950-1(ed.2);am2

As shown in the Test Report Ref. No. which forms part of this Certificate

ATTCB106089-01 issued on 2018-05-11

This CB Test Certificate is issued by the National Certification Body



- UL (US), 333 Pfingsten Rd IL 60062, Northbrook, USA
- UL (Demko), Borupvang 5A DK-2750 Ballerup, DENMARK
- UL (JP), Marunouchi Trust Tower Main Building 6F, 1-8-3 Marunouchi, Chiyoda-ku, Tokyo 100-0005, JAPAN
- UL (CA), 7 Underwriters Road, Toronto, M1R 3B4 Ontario, CANADA

For full legal entity names see [www.ul.com/ncbnames](http://www.ul.com/ncbnames)

Date: 2018-05-14

Signature:

Original Issue Date: 2018-01-09

Jan-Erik Storgaard



Ref. Certif. No.

**DK-69732-M1-UL**

**Model Details:**

xNUC6xAyX, xNUC7xBNHx, xNUC7xBNKx, xNUC7xJYx, xNUC8xBEHx, xNUC8xBEKx  
(where x can be a combination of alphanumeric characters, none or blank)

**Additional Information:**

Additionally evaluated to EN 60950-1: 2006 / A11: 2009 / A1: 2010 / A12: 2011 / A2: 2013  
National Difference specified in the CB Test Report

The original report was modified to include the following changes/additions:

- 1) update product information in model difference table.
- 2) add alternative sources of wireless network card for all models and update information in table 1.5.1.
- 3) add new model names with new configuration, see below for details:
  - add alternative sources of power adapter with new ratings.
  - add alternative sources of PC motherboards.
  - add alternative sources of external enclosure/ internal metal enclosure.

**Additional information (if necessary)**



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